

# L-Band Internally Matched Si-MMIC Front-End

Noriharu Suematsu, *Member, IEEE*, Masayoshi Ono, Shunji Kubo, Yoshitada Iyama, *Member, IEEE*, and Osami Ishida, *Member, IEEE*

**Abstract**—A 1.9 GHz-band internally matched Si-MMIC front-end, fabricated in standard 0.8  $\mu\text{m}$  BiCMOS process, was developed. This IC front-end contains a MOSFET T/R switch, a two-stage BJT low noise amplifier (LNA), and a down converter BJT mixer. Since the circuits are monolithically integrated on a low resistivity Si substrate, the coplanar waveguide (CPW) type spiral inductors are used to reduce the dielectric loss of on-chip matching circuits. The T/R switch has measured insertion loss of 2.5 dB and isolation of 25.5 dB at 0/3 V control voltage. The two-stage LNA has gain of 17.1 dB and noise figure (NF) of 2.9 dB at 2 V, 4 mA dc supply. The mixer has conversion gain of 5.9 dB and NF of 15 dB at 2 V, 1.7 mA dc supply. The measured performance of the fabricated Si-MMIC front-end indicates the possibility of application to mobile communication handset terminals.

## I. INTRODUCTION

IN RECENT years, there is an increasing demand for low production cost RF IC front-end used in handset terminals for mobile communication [1]–[4]. The Si-IC fabricated in BiCMOS process [3]–[5] is one of those developed for such applications. Since the standard BiCMOS process [6]–[7] uses relatively low resistivity Si substrate (about 10  $\Omega\text{ cm}$ ), the loss of on-chip matching circuits, especially that of spiral inductor, is quite high, due to the dielectric loss of Si substrate in the microwave frequency range [7]–[9]. For this reason, most of Si-IC's have used spiral inductors only as bias circuits, and have needed external matching circuits [3]–[5]. Some modifications of BiCMOS process have been tried to reduce the dielectric loss by using high resistivity (several  $\text{k}\Omega\text{ cm}$ ) Si substrate [10], or by using thick polyimide (10  $\mu\text{m}$  thickness) as insulator [8]. In this paper, the CPW type spiral inductor is described, which offers superior feature in comparison with microstrip (MS) type spiral inductor. By selecting CPW type spiral inductor for matching circuits, it is possible to reduce the insertion loss which comes from the dielectric loss of the low resistivity Si substrate. The configuration and the measured performance of the fabricated L-band Si-MMIC front-end with CPW type on-chip matching circuits are also described. This IC front-end contains an enhancement mode N-type MOSFET T/R switch [11], a two-stage bipolar junction transistor (BJT) LNA and a BJT mixer. The CPW type spiral inductors are used in the input and output matching circuits of the LNA and RF input and LO input matching circuits of the mixer.

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TABLE I  
EXTRACTED EQUIVALENT CIRCUITS PARAMETERS AND THE ATTENUATION OF CPW AND MS TYPE FOUR-TURN SPIRAL INDUCTORS. (OUTER SIZE: 300  $\mu\text{m} \times 300 \mu\text{m}$ , CONDUCTOR THICKNESS: 3.5  $\mu\text{m}$ , STRIPLINE WIDTH: 11  $\mu\text{m}$ , LINE SPACE: 10  $\mu\text{m}$ )

Type	CPW	MS
$L_s$	4.2	4.2
$C_p$	0.4	0.46
$R_s$ ( $\Omega$ )	4.6	3.3
$R_p$ ( $\Omega$ )	136	2.46
Attenuation (dB)	1.5	1.8

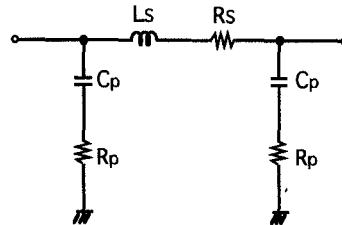


Fig. 1. Equivalent circuit of spiral inductor fabricated on low resistivity Si substrate.  $R_s$  represents the conductor loss,  $R_p$  represents the dielectric loss of the spiral inductor,  $L_s$  represents the inductance component of the spiral inductor, and  $C_p$  represents the stripline-substrate capacitance.

## II. FEATURES OF CPW TYPE SPIRAL INDUCTOR

The loss of spiral inductors is dominant among the losses of the internal matching circuits for L-band LNA and mixer used in RF front-end. In order to reduce the conductor loss, the stripline thickness of 3.5  $\mu\text{m}$  is achieved by stacking second, third and fourth aluminum conductor layer. Then the reduction of dielectric losses of low resistivity Si substrate is desirable. Equivalent circuit parameters and attenuation are compared between CPW and MS type spiral inductor. The equivalent circuits of spiral inductor fabricated on a low resistivity Si substrate is shown in Fig. 1. Series resistance  $R_s$  represents the conductor loss and parallel resistance,  $R_p$  represents the dielectric loss of the spiral inductor,  $L_s$  represents the inductance component of the spiral inductor, and  $C_p$  represents the stripline-substrate capacitance. Table I shows the extracted equivalent circuits parameters and the attenuation of CPW and MS type four-turn spiral inductors having 300  $\mu\text{m} \times 300 \mu\text{m}$  outer size, 3.5  $\mu\text{m}$  aluminum conductor thickness, 11  $\mu\text{m}$  stripline width and 10  $\mu\text{m}$  line space. The resistivity of Si substrate is about 10  $\Omega\text{cm}$ , and the insulator between aluminum stripline and Si substrate is 1  $\mu\text{m}$  thick  $\text{SiO}_2$  layer. In the case of the CPW,  $R_s$  is 40% higher and  $R_p$  is 45% lower than that in the case of the MS. In this case, the CPW type spiral inductor has 22% lower attenuation than MS type spiral inductor has, because of the lower  $R_p$ , that is, lower dielectric loss.

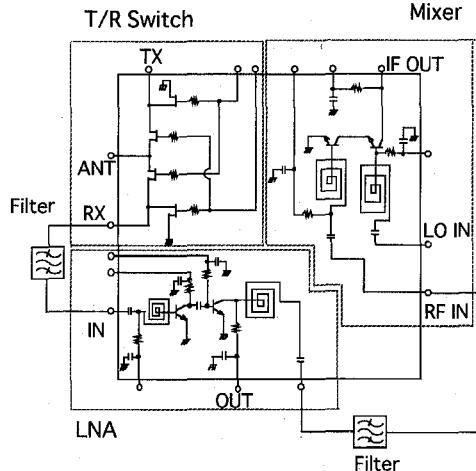
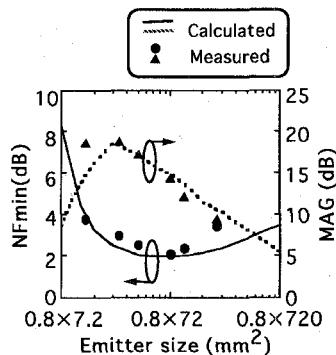


Fig. 2. Schematic diagram of Si-MMIC front-end.

Fig. 3. Emitter size dependence of BJT's  $NF_{min}$  and MAG measured at 1.9 GHz. The bias condition is  $V_{ce} = 1.2$  V,  $I_{ce} = 2$  mA. The calculated data derived from extracted SPICE parameters. The lowest  $NF_{min}$  of 1.9 dB and MAG of 14.5 dB are achieved at emitter size of  $0.8 \mu\text{m} \times 72 \mu\text{m}$ .

### III. CONFIGURATION OF IC FRONT-END

The schematic diagram of Si-MMIC front-end is shown in Fig. 2. This IC consists of a MOSFET T/R switch, a two-stage BJT low noise amplifier (LNA), and a down converter BJT mixer. External filters can be connected between RX port of T/R switch and IN port of LNA and between OUT port of LNA and RF IN port of mixer. In order to obtain higher isolation, all bias circuits are separated among T/R switch, LNA, and mixer.

#### A. T/R Switch

Enhancement mode  $N$  type MOSFET's (gate length ( $L_g$ ) =  $0.8 \mu\text{m}$ , gate width ( $W_g$ ) =  $400 \mu\text{m}$ , both are in mask size) are used as switching elements, and are switched by gate control voltage of 0 V (OFF state)/3 V (ON state). All control bias ports are connected to FET gate through  $2 \text{ k}\Omega$  resistors. In order to achieve higher isolation in OFF state, the FET's are series-shunt connected.

#### B. LNA

There is an optimum emitter size to achieve the lowest  $NF_{min}$  under the constant dc supply current and voltage. In

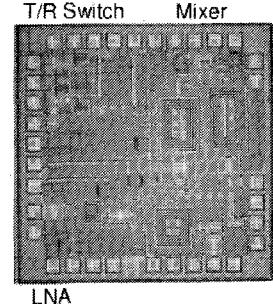
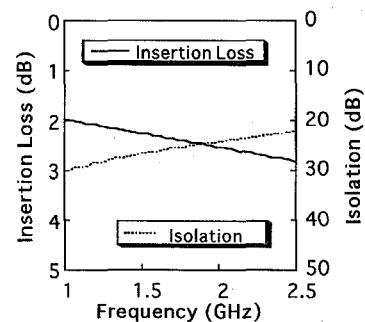
Fig. 4. Photograph of fabricated Si-MMIC front-end with internal matching spiral inductors. The chip size is  $2 \text{ mm} \times 2 \text{ mm}$ .

Fig. 5. Small signal characteristics of T/R MOSFET switch. The control voltage is 0 V (off state) and 3 V (on state). The insertion loss is 2.5 dB and the isolation is 25.5 dB at 1.9 GHz.

the case of smaller emitter size, the  $NF_{min}$  increases with increasing base resistance. On the other hand, in the case of larger emitter size, the  $NF_{min}$  increases with decreasing current density per unit emitter size. The emitter size dependence of the BJT's  $NF_{min}$  and maximum available gain (MAG) measured at 1.9 GHz is shown in Fig. 3. The calculated data derived from extracted SPICE parameters. With 1.2 V and 2 mA dc supply, the lowest  $NF_{min}$  of 1.9 dB and MAG of 14.5 dB are achieved at emitter size of  $0.8 \mu\text{m} \times 72 \mu\text{m}$  (mask size). Then the emitter size of BJT for LNA is designed as  $0.8 \mu\text{m} \times 72 \mu\text{m}$ . The input port is NF matched, and the output port is gain matched to  $50 \Omega$  internally, by using CPW type spiral inductors. The collectors of the BJT's are biased through  $400 \Omega$  resistor. The collector-emitter voltage of both BJT's is 1.2 V at supplied dc current of 2 mA each and voltage of 2 V.

#### C. Mixer

Two BJT's, having same emitter size as those used in LNA, are connected in series. RF and LO signals are introduced to the base of BJT's separately. RF and LO ports are internally matched by using CPW type spiral inductors and resistor. The collector is biased through  $400 \Omega$  resistor which is connected to IF output. IF port requires external matching circuits.

### IV. MEASURED RESULTS

A photograph of fabricated Si-MMIC front-end with internal matching spiral inductors is shown in Fig. 4. The chip size is

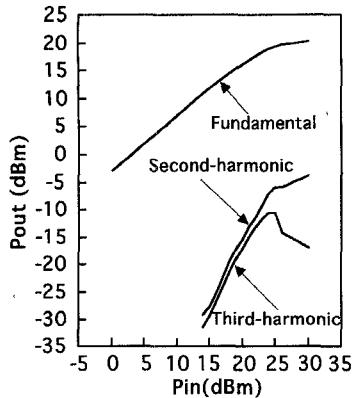


Fig. 6. Transfer characteristics of T/R MOSFET switch measured at 1.9 GHz. The control voltage is 0 V (off state) and 3 V (on state). The insertion loss degradation begins at input power of 23 dBm.

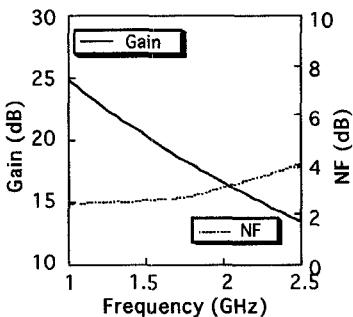


Fig. 7. Frequency dependence of gain and NF of two-stage BJT LNA. The bias condition is  $V_{cc} = 2$  V,  $I_{ce} = 4$  mA (2 mA for each BJT). The gain is 17.1 dB and the NF is 2.9 dB at 1.9 GHz.

2 mm  $\times$  2 mm, and the IC is fabricated in standard 0.8  $\mu$ m BiCMOS process [6]. All spiral inductors consist of 3.5  $\mu$ m thick and 11  $\mu$ m wide aluminum stripline.

The small signal characteristics of T/R switch is shown in Fig. 5. The insertion loss is 2.5 dB and the isolation is 25.5 dB at 1.9 GHz. The transfer characteristics of T/R switch measured at 1.9 GHz is shown in Fig. 6. The insertion loss degradation begins at input power of 23 dBm. Up to 30 dBm, the FET destruction can not be observed. In order to improve the insertion loss and the saturated power, adopting lower threshold voltage FET or/and silicided source-drain structure FET will be a candidate.

The frequency dependence of gain and NF of two-stage BJT LNA is shown in Fig. 7. The loss of dc cut capacitors at input and output ports is excluded. The bias condition is  $V_{cc} = 2$  V,  $I_{ce} = 4$  mA (2 mA for each BJT). The gain is 17.1 dB and the NF is 2.9 dB at 1.9 GHz. The frequency dependence of return loss of the LNA is shown in Fig. 8. Since the input port is NF matched, the input return loss is 7.0 dB, but the output return loss is 16.6 dB at 1.9 GHz. Both ports are matched in a wide band, because of the relatively low  $Q$  spiral inductor.

The frequency dependence of conversion gain and NF of BJT mixer is shown in Fig. 9. This performance excludes the loss of dc cut capacitor at both RF and LO input ports. The bias condition is  $V_{cc} = 2$  V,  $I_{ce} = 1.7$  mA, and LO power is

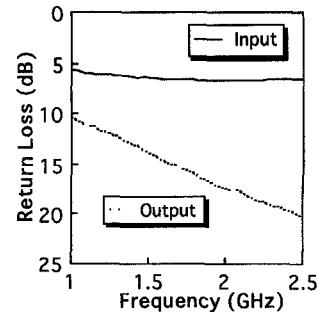


Fig. 8. Frequency dependence of return loss of two-stage BJT LNA. The bias condition is  $V_{cc} = 2$  V,  $I_{ce} = 4$  mA (2 mA for each BJT). The input return loss is 7.0 dB and the output return loss is 16.6 dB at 1.9 GHz.

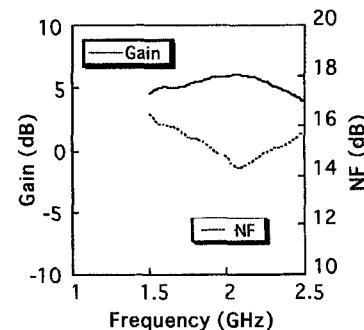


Fig. 9. Frequency dependence of conversion gain and NF of BJT mixer. The bias condition is  $V_{cc} = 2$  V,  $I_{ce} = 1.7$  mA, IF frequency is 240 MHz, and LO power is 0 dBm. The conversion gain is 5.9 dB and the NF is 15 dB at 1.9 GHz RF frequency.

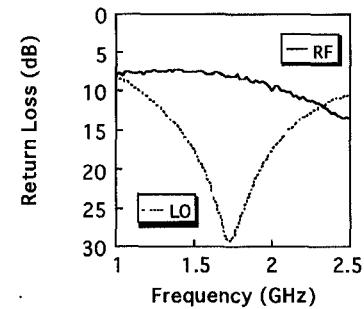


Fig. 10. Frequency dependence of RF and LO return loss of BJT mixer measured at 0 dBm LO power. The bias condition is  $V_{cc} = 2$  V,  $I_{ce} = 1.7$  mA. When RF frequency is 1.9 GHz and LO frequency is 1.66 GHz, the return loss is 8.0 dB at RF input port and 21 dB at LO input port.

0 dBm. The conversion gain is 5.9 dB and the NF is 15 dB at 1.9 GHz RF frequency. The frequency dependence of RF and LO return loss of the mixer measured at 0 dBm LO power is shown in Fig. 10. When RF frequency is 1.9 GHz and LO frequency is 1.66 GHz, the return loss is 8.0 dB at RF input port and 21 dB at LO input port. The LO power dependence of conversion gain and NF of the mixer is shown in Fig. 11. RF frequency is 1.9 GHz, and IF frequency is 240 MHz. Below  $-10$  dBm LO power, the conversion gain rapidly decreases, and the NF rapidly increases.

By using this IC, the RF front-end having NF of 6.6 dB, including T/R switch, can be realized at 1.9 GHz with 11.4 mW dc power consumption.

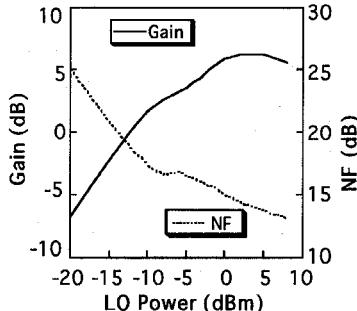


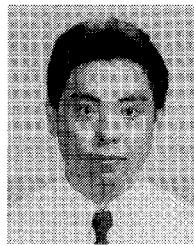
Fig. 11. LO power dependence of conversion gain and NF of BJT mixer. The RF frequency is 1.9 GHz, and IF frequency is 240 MHz. The bias condition is  $V_{cc} = 2$  V,  $I_{ce} = 1.7$  mA. Below  $-10$  dBm LO power, the conversion gain rapidly decreases, and the NF rapidly increases.

## V. CONCLUSION

An L-band Si-MMIC front-end with fully monolithic internal matching circuits was developed. This IC is fabricated on a low resistivity Si substrate in standard  $0.8\ \mu\text{m}$  BiCMOS process. It contains a T/R switch, a two-stage LNA and a down converter mixer. By using CPW type spiral inductors, on-chip matching circuits with lower insertion loss can be achieved. The performance of this IC front-end at 1.9 GHz with low dc power consumption shows the possibility of application to mobile handset terminals.

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